

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10551817	LIN ET AL..	
	Examiner	Art Unit	
	Cheng, Ichieh	4183	

SEARCHED

Class	Subclass	Date	Examiner
455	452.1-452.2,436,442	1/3/2009	SR
370	310.1,331,338	7/29/2008	SR

SEARCH NOTES

Search Notes	Date	Examiner
EAST	1/3/2009	SR

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/SHARAD RAMPURIA/ Primary Examiner, Art Unit 2617
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